



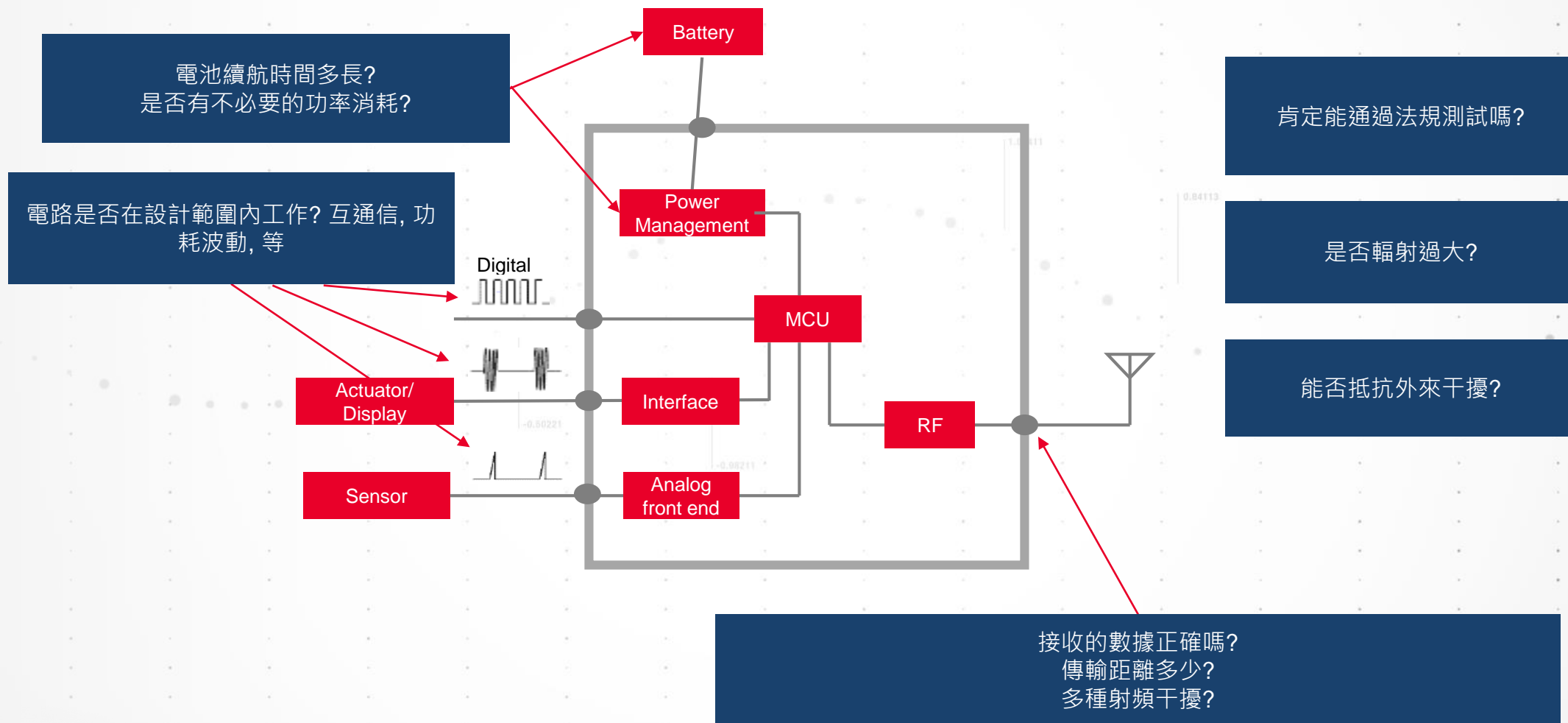
克服物聯網功耗與生產挑戰



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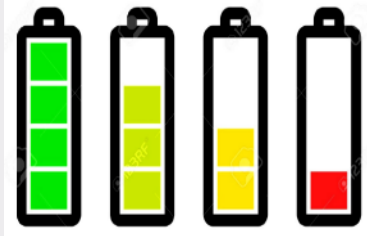
IoT終端測試的挑戰



Top challenges for IoT devices

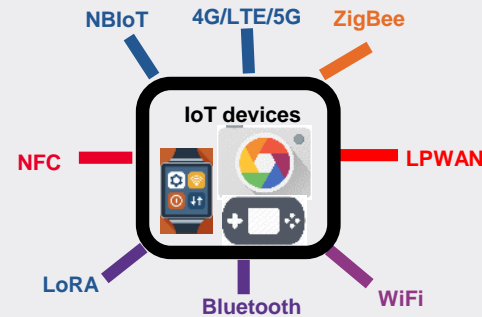
THE CHALLENGES FROM R&D, MANUFACTURING TO DEPLOYMENT

Energy Efficiency



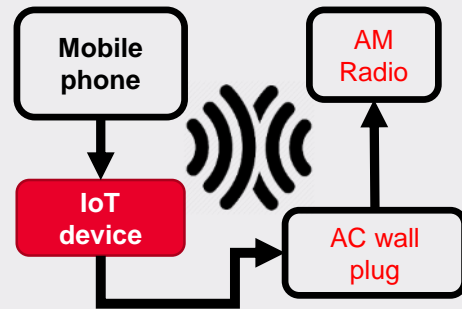
- Maximize battery run time
- Design trade off:
 - Battery type & capacity
 - Processing power
 - Component size & quality
 - Cost
 - Firmware behaviour

Multi-Technologies & Standards



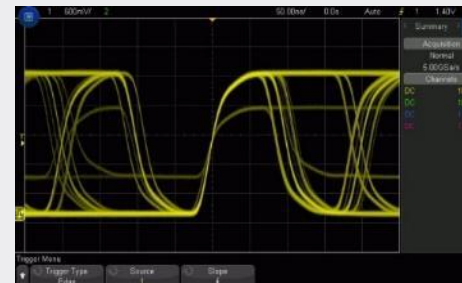
- Complex testing
- Fast evolving standards
- Device interoperability
- Inter and intra-device interference
- Wireless coexistence

Interference, Compliance, Regulatory test



- Radiated emission
- Radiated immunity
- Conducted emission
- Conducted immunity
- Spectrum regulatory

Signal and Power Integrity



- Reflections / crosstalk
- Impedance mismatch
- Excessive losses and noise
- Unwanted transients
- Voltage drops
- Overheating
- Jitter, clock and data error

Top challenges for IoT devices – the solutions

THE CHALLENGES FROM R&D, MANUFACTURING TO DEPLOYMENT

Energy Efficiency

DMM **Scope and Current Probe** **DC Power Analyzer** **Source/Measure Unit (SMU)** **Device Current Waveform Analyzer**

Increasing Accuracy and Insight →

Multi-Technologies & Standards

UXM	X-series SA/SG	EXM	Fieldfox
Signaling Test	R&D Validation	Manufacturing	Deployment
Call Processing	Rx Sensitivity	Calibration	Spectrum Clearance
Protocol	Tx RF Performance	Rx Sensitivity	Installation
RF Performance	Regulatory Pre-compliance	Tx RF Performance	Interference hunting
Application	Tx Modulation Quality	Tx Modulation Quality	Repair

Interference, Compliance, Regulatory test

Keysight IoT Pre-compliance Test Solution

X-series Signal Analyzer + N6141A EMI Measurement Application + N33113-100 Close Field Probe

Field Interference Test Solutions

Fieldfox with option 350 (RTSA) Interfering signal is buried inside downlink carrier in traditional SA Fieldfox RTSA detects interfering signal that is hard to detect with traditional SA (with density display)

Signal and Power Integrity

N7020A Power Rail Probe **N8833A Crosstalk Analysis App**

Good **Better** **Best**

InfiniiVision 3000 & 4000 X-Series InfiniiVision 6000 X-Series Infiniium S-Series

新發報: IoT 終端設計和測試方案

KESYSIGHT全方位測試方案, 克服各種挑戰

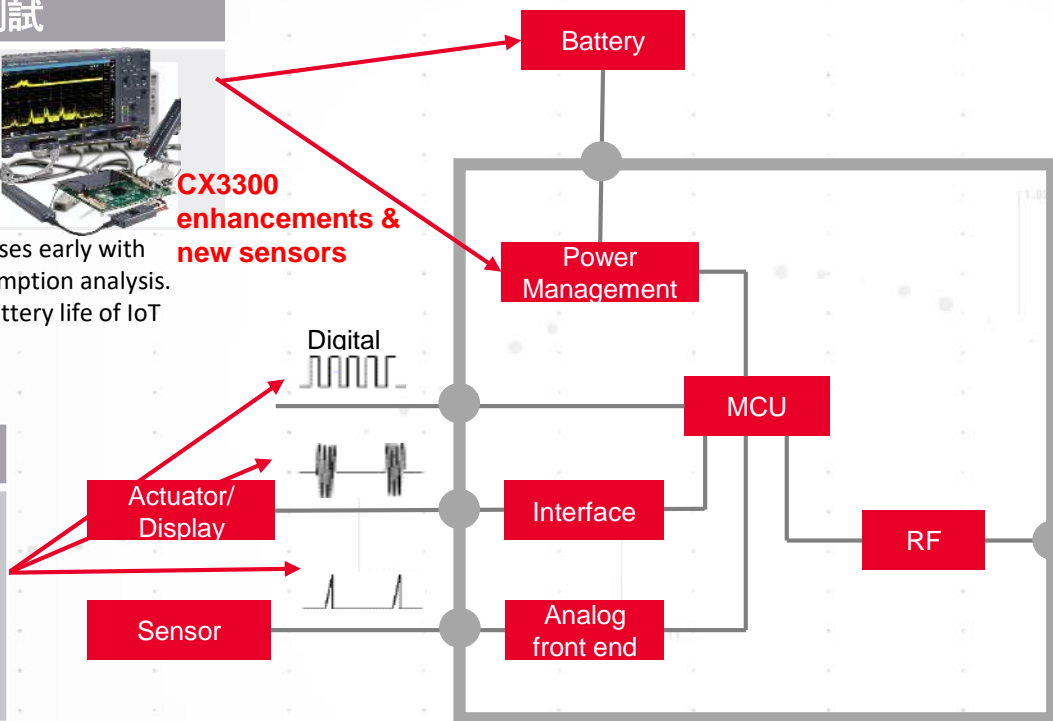
功耗測試

X8712A
IoT Device
Battery Life
Optimization
Solution

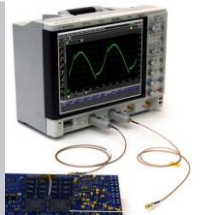


Detect design weaknesses early with event based power consumption analysis. Accurately predict the battery life of IoT devices.

CX3300
enhancements &
new sensors



信號完整性測試



Best visibility of your signal and data integrity issues

模擬和設計軟件



Complete tools for ecosystems from component, IC, Board to System level.

法規和一致性測試



One box for EMI and spectrum regulatory pre-compliance tests

Conformance test systems for operator acceptance test

用於生產的OTA 功能測試



X8711A
IoT Device
Functional
Test
Solution

Failproof your IoT device against the rigors of real world

無線共存測試



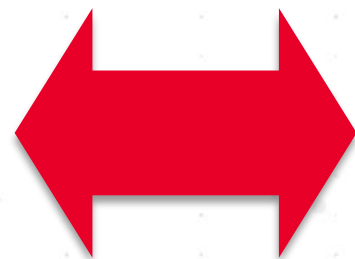
**LoRa物理層
測試**

**Ixia
VeriWave**

X8712A IoT 設備電池續航時間優化方案



關鍵的電池續航時間



	SIGFOX	LoRaWAN	NB-IoT	Cat M	EC-GPRS
Release	Now	Now	H2 2016	H2 2016	H2 2016
Link budget	~162dB	~157dB	~164dB	~156dB	~164dB
Battery life	>10 years	>10 years	>10 years	>10 years	>10 years
Spectrum	un & lightly-license bands e.g. 868, 915 MHz	un & lightly-license bands e.g. 169, 433, 470, 868, 915 MHz	GSM & LTE Licensed bands	LTE Licensed bands	GSM Licensed bands
Rates and modulation	Uplink: 100bps BPSK 100Hz BW Downlink: 500bps GFSK 600Hz BW	GFSK, CSS (Chirp Spread Spectrum) ~0.3 to 50kbps 125kHz BW	Up to ~250kbps Uplink $\pi/4$ -QPSK, rotated $\pi/2$ BPSK, 8PSK, opt 16QAM Downlink BSK-16QAM 180kHz BW	1Mbps QPSK, 16 or 64QAM 1.4MHz BW	~10 to ~240kbps GMSK, opt 8PSK, 200kHz BW
Silicon	Multi-vendor	Semtech (2 nd vendor announced)	Multi-vendor	Multi-vendor	TBC
Protocol	SIGFOX	Semtech (2 nd vendor announced)	3GPP Multi-vendor	3GPP Multi-vendor	3GPP Multi-vendor
Certification	SIGFOX	LoRa Alliance	GCF/PTCRB TBC	GCF/PTCRB TBC	GCF/PTCRB TBC

挑戰:

1. 如何定義電池的續航時間?
2. 什麼東西/情況最耗電? 這種情況的頻次很大嗎?
3. 什麼設計改變或可以優化電池的續航時間?

當前電流測試的常用方法

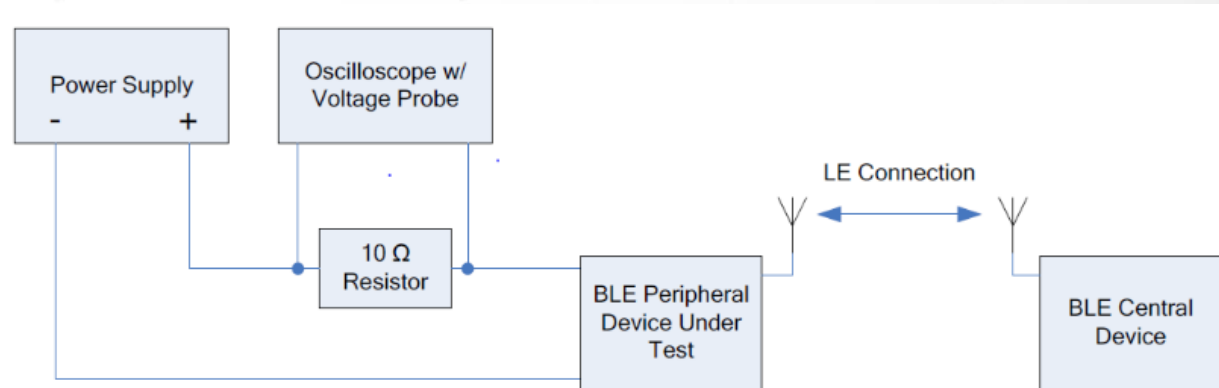
電源, DMM 和示波器



DMM



電源

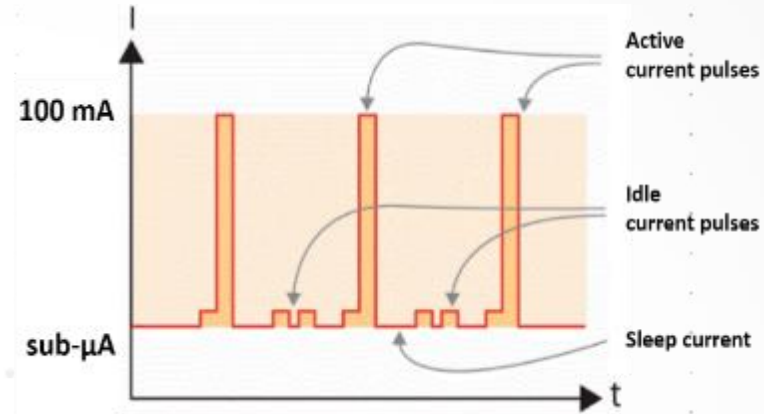


示波器+電流探頭

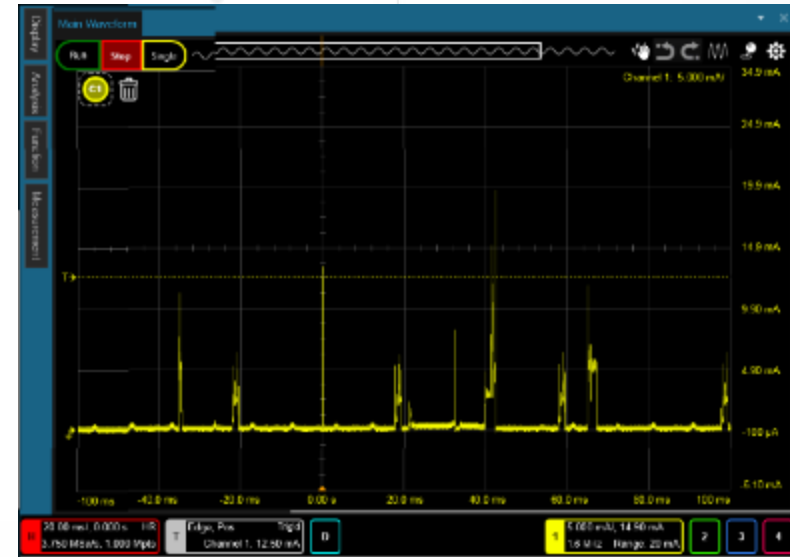
容易用, 靈活, 成本低

IoT 電流測試為何難？

- 睡眠/待機模式電流非常低
- 高動態電流切換需要高帶寬
- 功耗分析複雜(事件->功耗)



無線血壓計的電流



可穿戴設備的電流

優化 IoT 終端電池續航時間的新方案

KEYSIGHT X8712A

同步RF事件和功耗水平

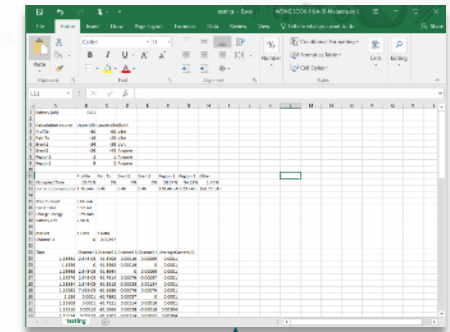
- Easily correlate current consumption to critical RF events
- Pinpoint critical events consuming the most current

可深入分析功耗情況

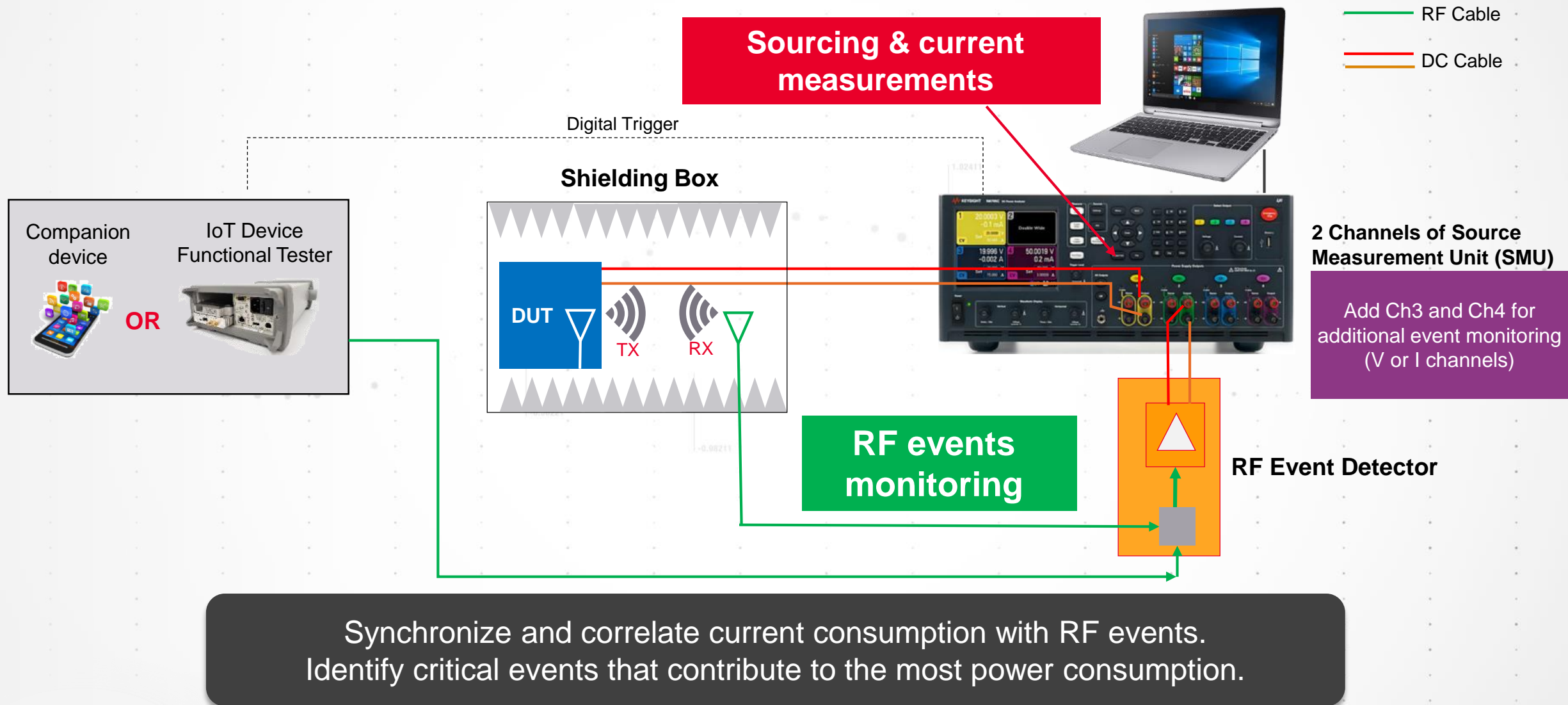
- Calculate RF or DC event's occupancy time and current consumption contribution in percentage to get the estimated battery life in hours according to the measured event
- Statistical current consumption CCDF analysis by user defined time span

數據記錄容易

- Simplify report creation
- Log event occupied time, current consumed and estimated battery life
- Online instrument control or off-line data record for real time comparison and future post analysis



X8712A Battery Life Optimization Solution in Action



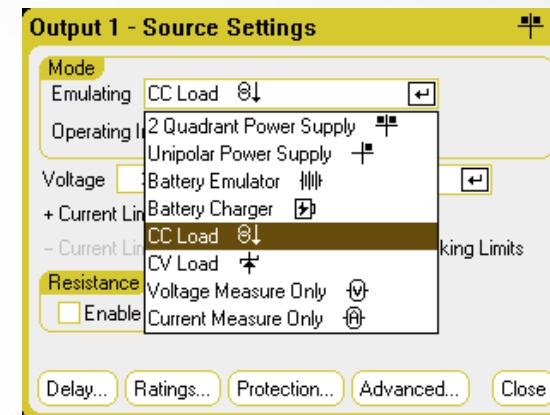
X8712A 基於事件的功耗分析系統簡介



DC 功率分析儀

Integrates multiple instrument functions into a single system:

- 1 to 4 advanced power supplies
- Digital voltmeter and ammeter
- Arbitrary waveform generator
- Oscilloscope-like display
- Data Logger
- ✓ All functions and measurements are available from the front panel
- ✓ Boosts the productivity of the R&D Engineer



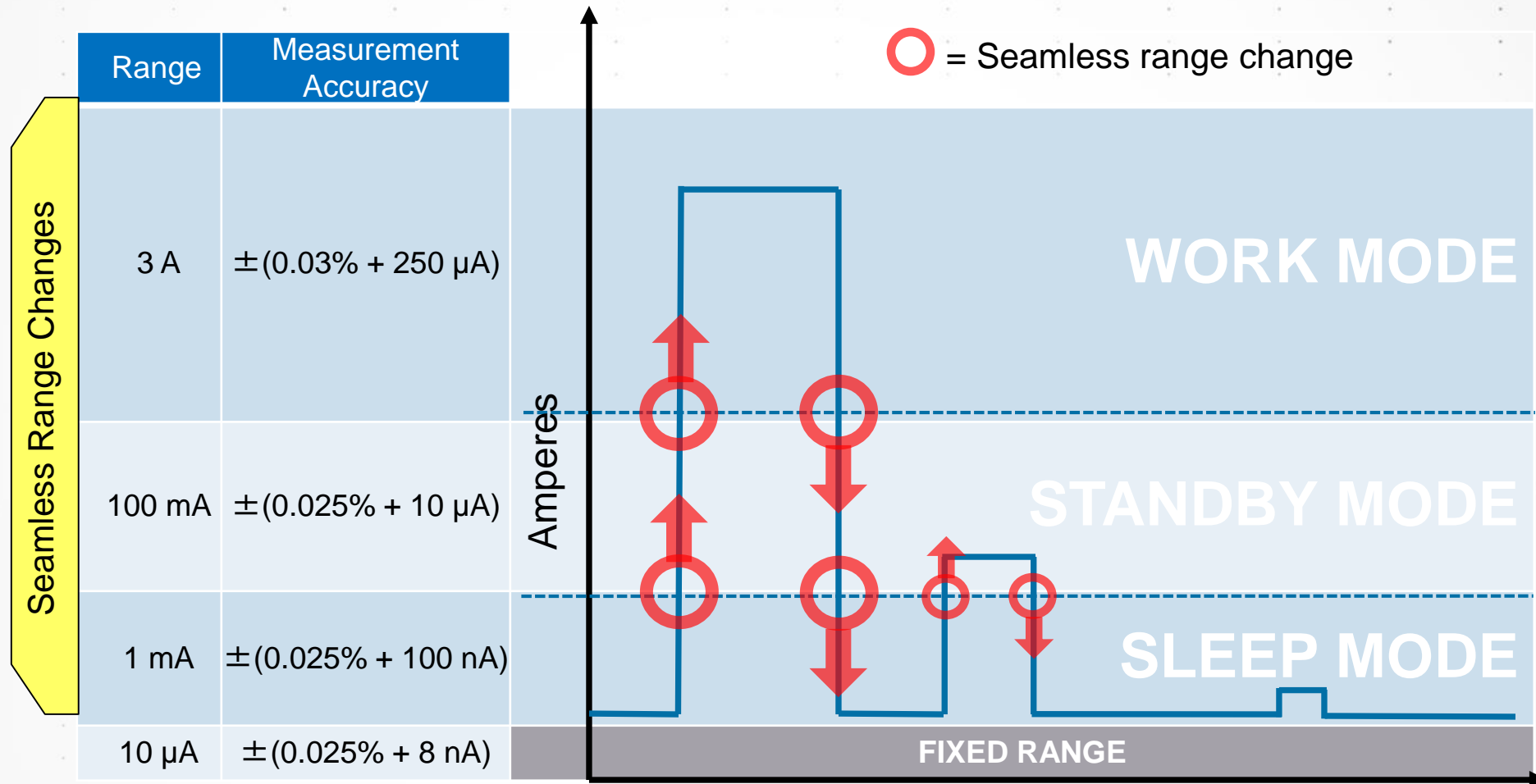
電源模塊 2-象限 SMU

Voltage Source
Current Source
Electronic Load

3 合 1

- “Glitch free” sourcing and measurement
- Multiple measurement ranges or seamless auto
- Excellent transient response to pulse sourcing
- Stable with capacitive loads up to 150 μ F
- Programmable output resistance simulates battery internal resistance
- Zero burden ammeter
- Auxiliary voltage measurement input for battery rundown test
- Measurement
 - Built-in digitizer of 200,000 samples/second

X8712A Key System Specification – Seamless Measurement

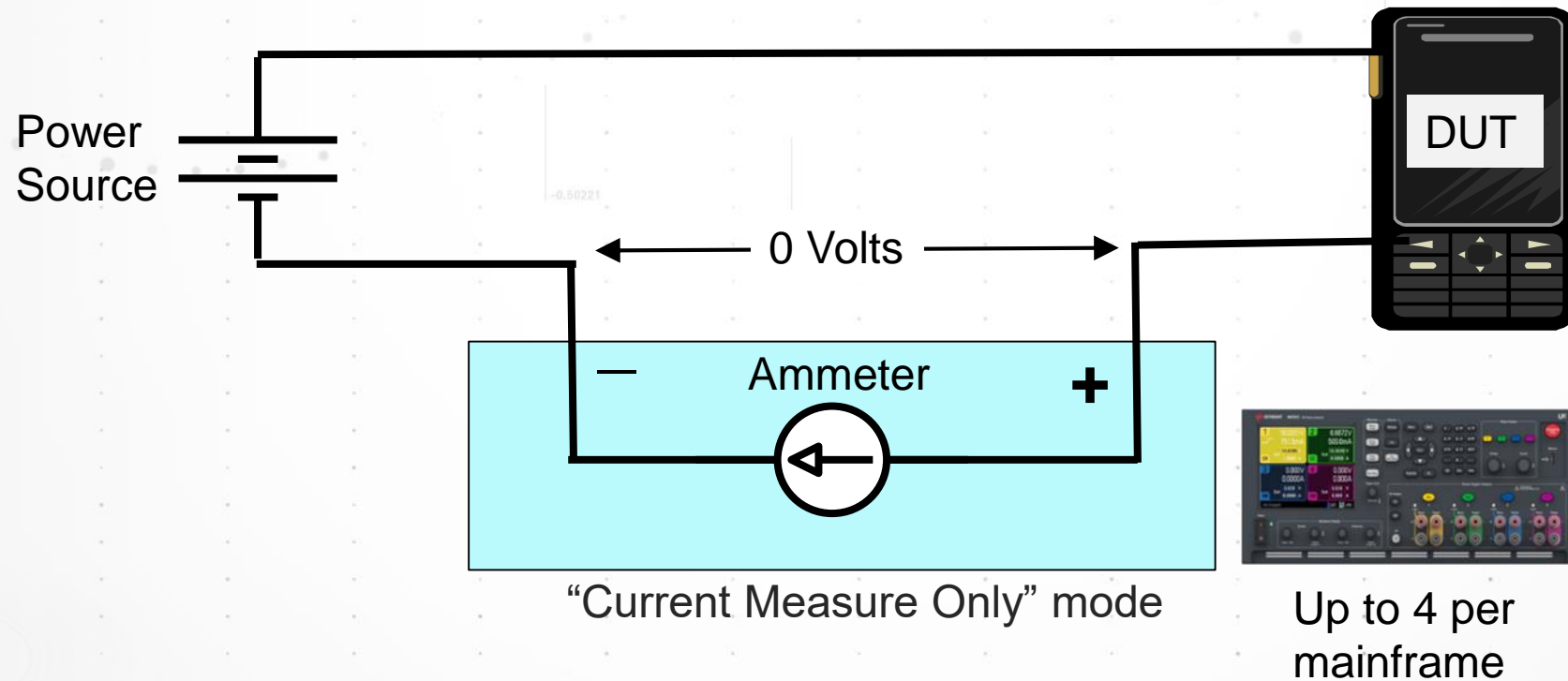


**See the complete current waveform you've never seen before
– from nA to A –
in one pass and one picture, with effective 28-bit resolution**

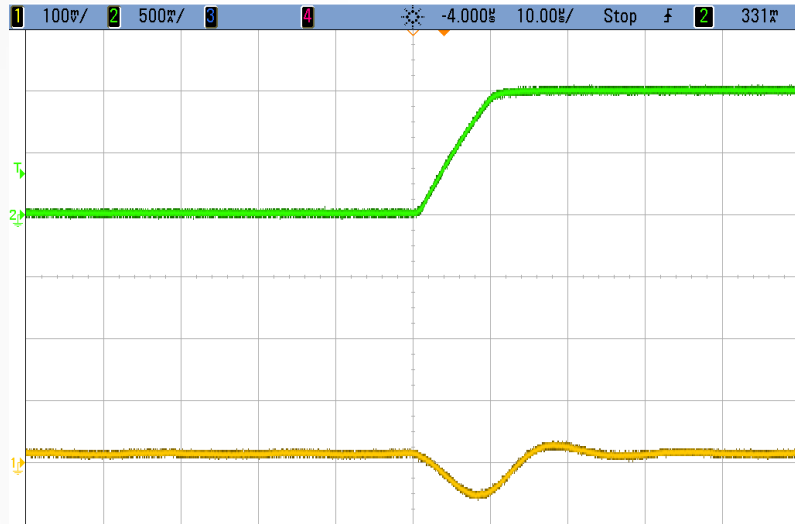
Key System Specification - Zero Burden Ammeter

Zero-Burden Ammeter (Single reading, Scope or Data log)

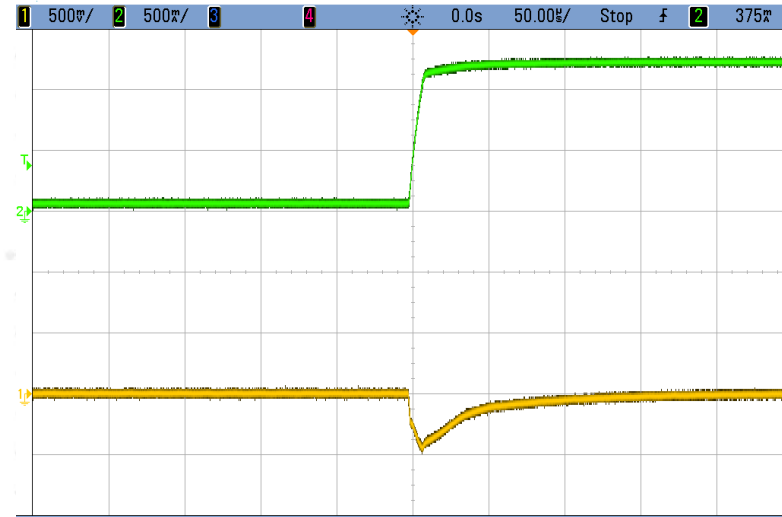
- Put SMU module in series with your power source and your DUT
- You source the current while the SMU module measures current flow
- SMU module uses its power output to regulate zero volts across itself while measuring current (in either direction of flow)
- No simulation: Most realistic way to determine how DUT will work on battery



Key System Specification - Fast Voltage Transient Response Performance



N6781A (high performance Source Measure Unit SMU) providing ~60 mV transient drop



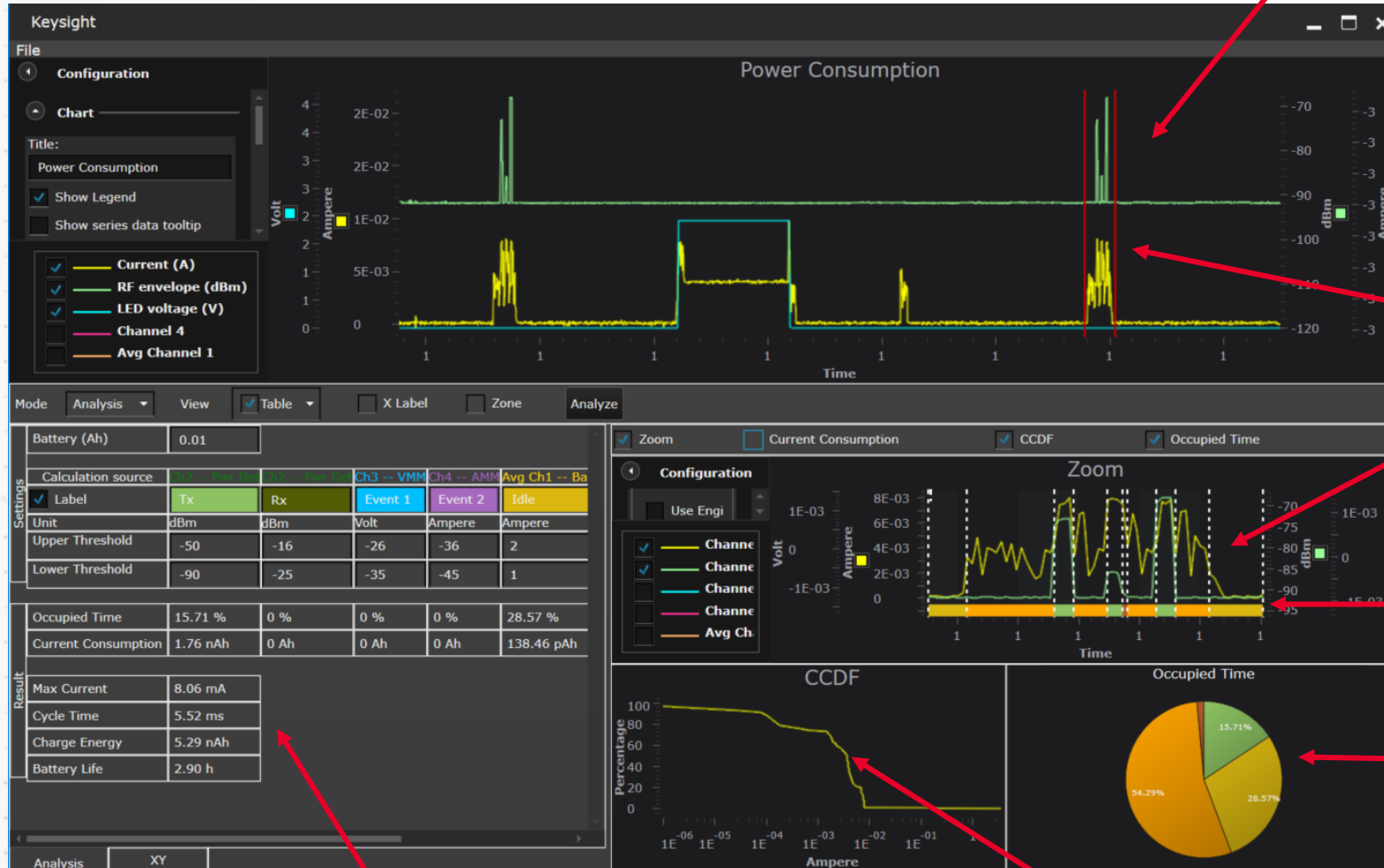
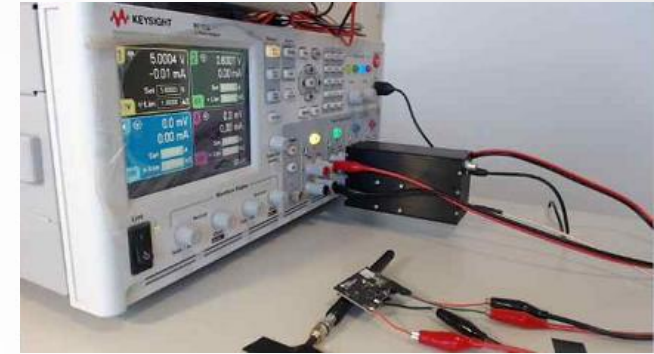
N6762A (a general purpose power supply module) providing ~500 mV transient drop

- Mobile digital wireless devices draw current in fast pulses
- Requires a stable voltage with minimum transient voltage drop
- The N678xA SMUs provide about 8X or better performance over GP DC sources
- The same transient response is achieved regardless of seamless ranging operation!

BLE傳感器測試演示

BLE/WLAN SENSOR TAG EVENT MONITORING

Yellow : DUT Current consumption
 Green : RF Transmissions between DUT companion device
 BLUE: LED supply voltage



Waveform Zoom & Analysis

Events Tags

Occupied Time by event

Event based analysis
 (Max current, cycle time, charge energy, battery life, occupied time, current consumption, and more)

Current CCDF

測試案例 #1: LoRa 模塊測試

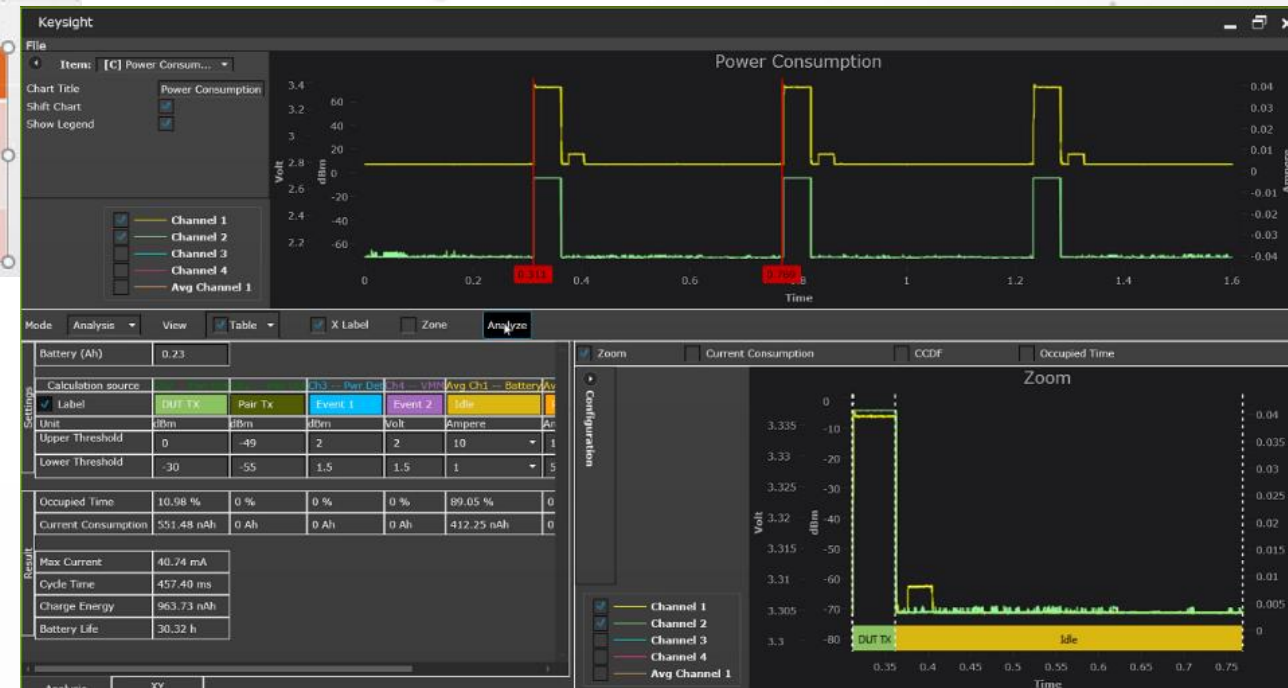
CUSTOMER APPLICATION EXAMPLE



The battery life of LoRa module varies depending on the signaling condition it is operating in. We can vary the spreading factor and measure the changes in maximum current and battery life. We can also use this info to help us choose the appropriate battery capacity to meet the battery life specification.

Packet transmission efficiency

Spread Factor	Max Current (mA)	Battery Life (Hr)	COT (%)
7	40.74	30.32	10.97
8	40.74	22.92	17.8
9	39.9	17.25	26.92



Customer's LoRa Module Current Waveform

NORMAL MODE OPERATION



RF signal in dBm

Current consumption waveform

Statistical data tools

Key readings

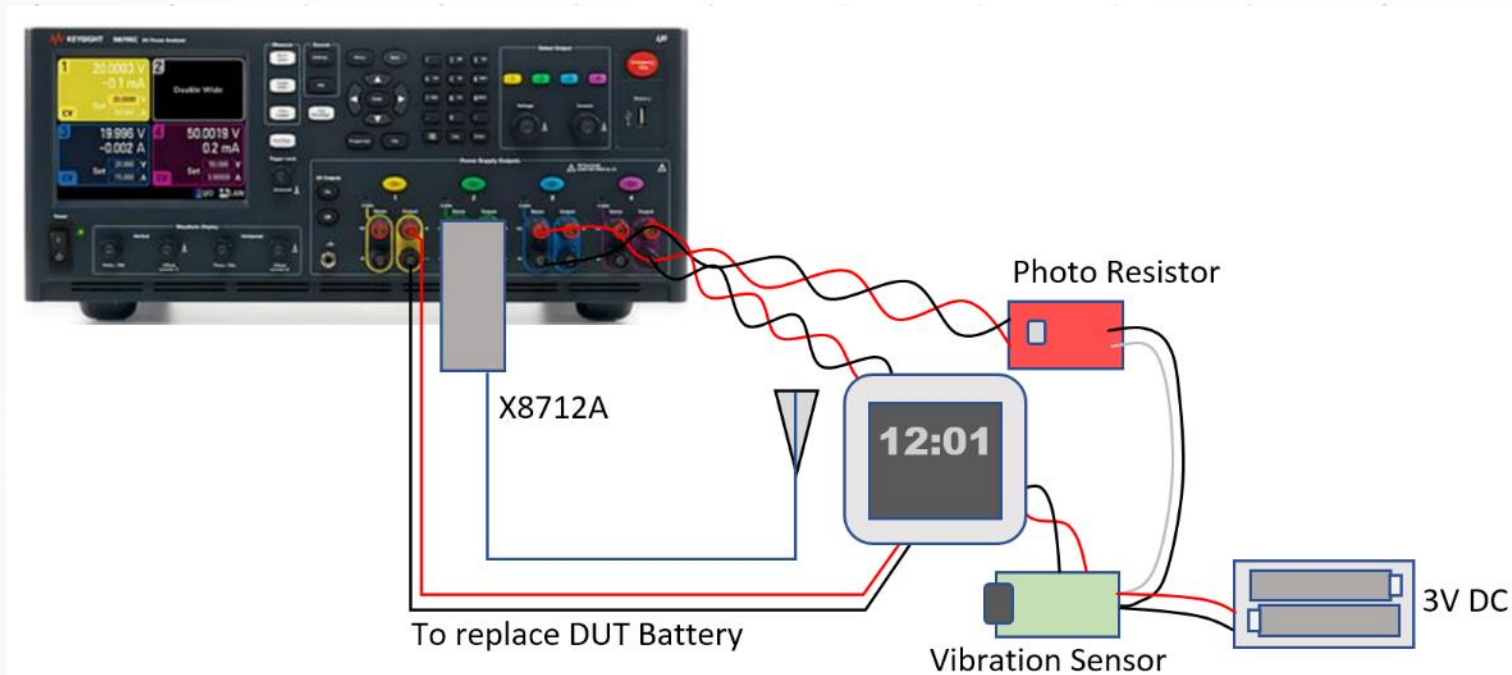
LoRa Module Current Spike

IRREGULAR CURRENT SPIKE IN SLEEP MODE



測試案例 #2: 智能可穿戴設備

CUSTOMER APPLICATION EXAMPLE



Test Setting:

Ch-1: Battery Simulator, 4V/1A, connects smart watch as the battery.

Ch-2: Voltmeter, CC-Mode/0A, connects to a 2.4GHz antenna placing near the DUT via the X8712A RF Event Detector

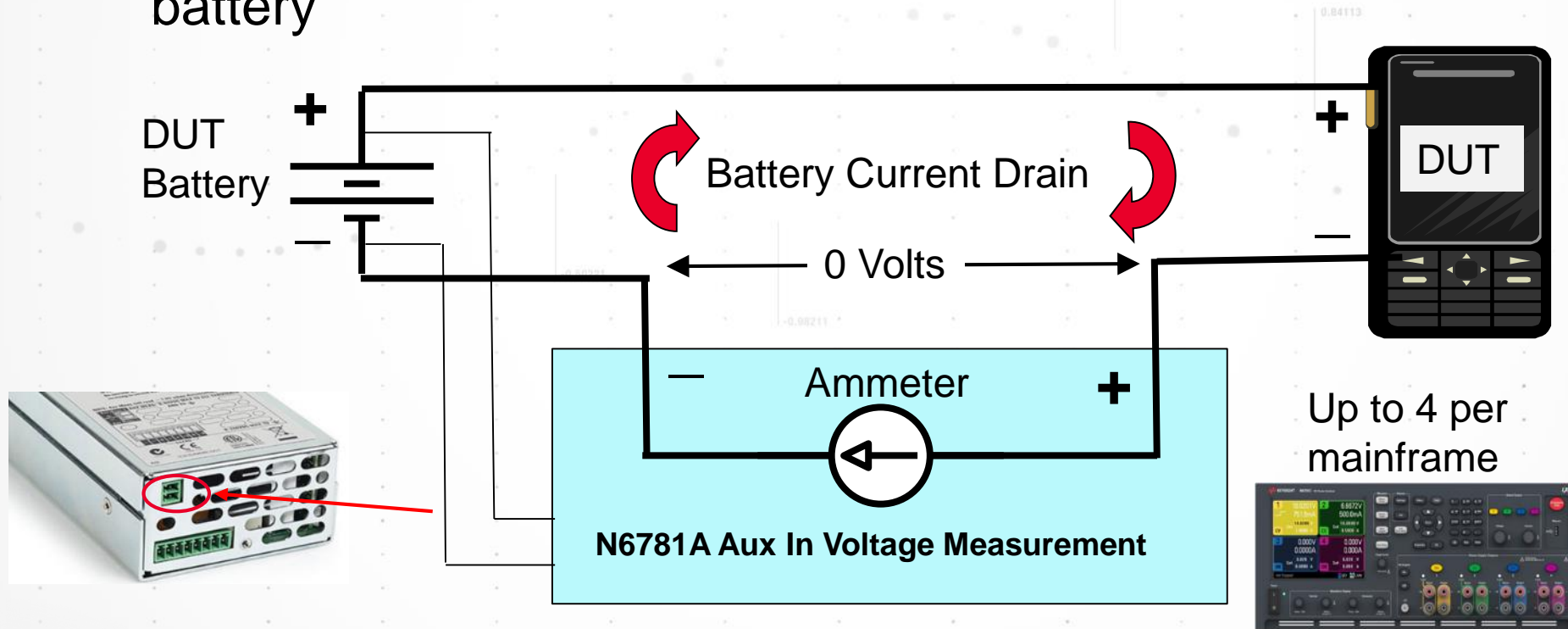
Ch-3: Voltmeter, connects to the photoresistor.

Ch-4: Voltmeter, connects to the vibration sensor.

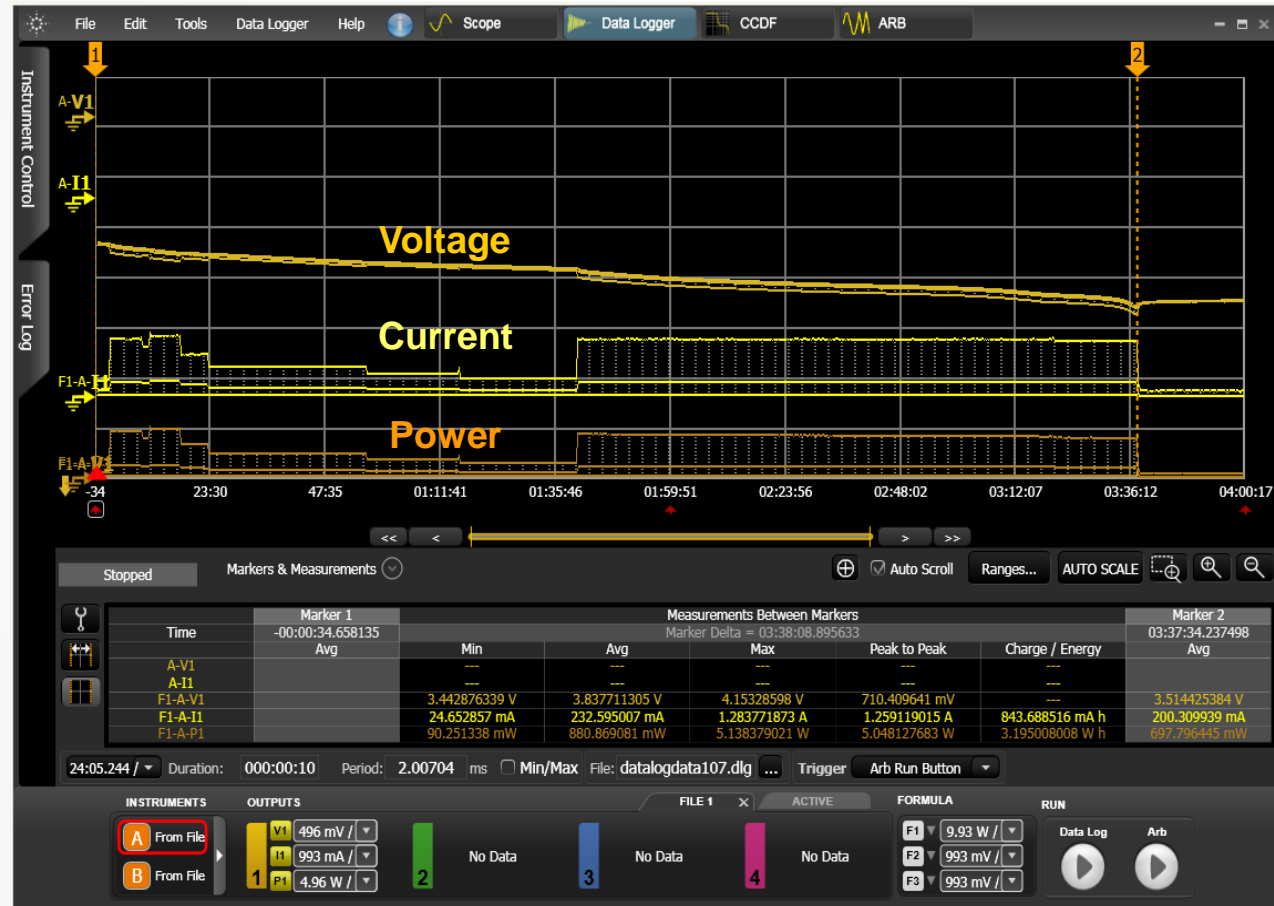
The photoresistor is about 1V in the dark and 1.5 to 2.5V in the light (depending on the brightness level). Note that the vibration sensor requires an additional 3V DC supply. The actual operating of all sensors in the watch is powered by the build-in battery cell.

Other Application #1: Battery Run Down using Zero-Burden Ammeter

- Module uses its power output to regulate zero volts across itself while measuring current (in either direction of flow)
- Single reading, scope, or data log
- N6781A Aux DVM input measures battery voltage
- Gives most realistic assessment of DUT operation with actual battery



Other Application #1: Battery Run-down Test Example



- Battery run-down for a GSM/GPRS handset logged with an N6781A SMU
- Logged min, avg & max volts, amps, & watts
- By placing markers at start & shutdown points:
 - Avg current = 233 mA
 - Avg voltage = 3.82 V
 - Charge = 843 mA h
 - Energy = 3.19 W h
 - Run time = 3 hr 38 min

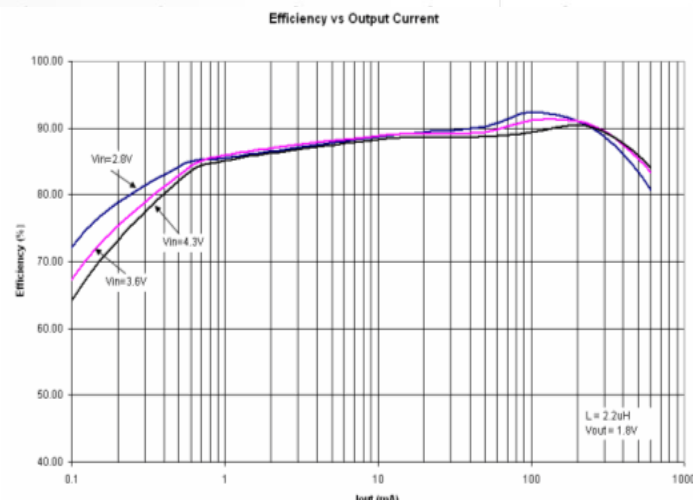
Other Application #2: DC-DC Converters Measurements

Typical Design Validation Measurements

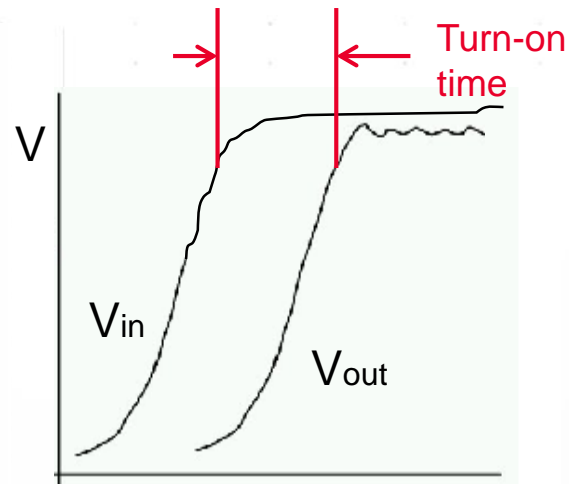
- Power efficiency vs. load current vs. input voltage
- Transient response
 - Output V & I vs. Input V (line regulation)
 - Output V vs. Output I (load regulation)
 - Start-up and shut-down times (impacts how quickly a circuit can be turned on/off which affects battery life)
 - Output V rise times



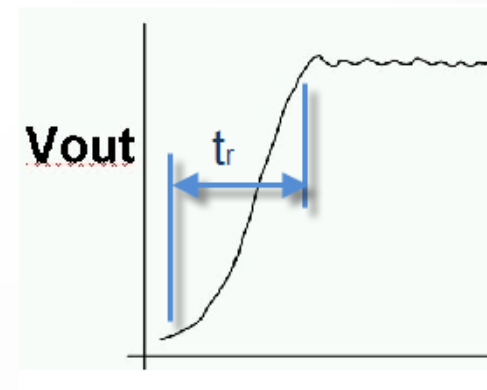
Customer Goal: Longer Operational (Battery) Life



Efficiency vs. I_{out} vs. V_{in}

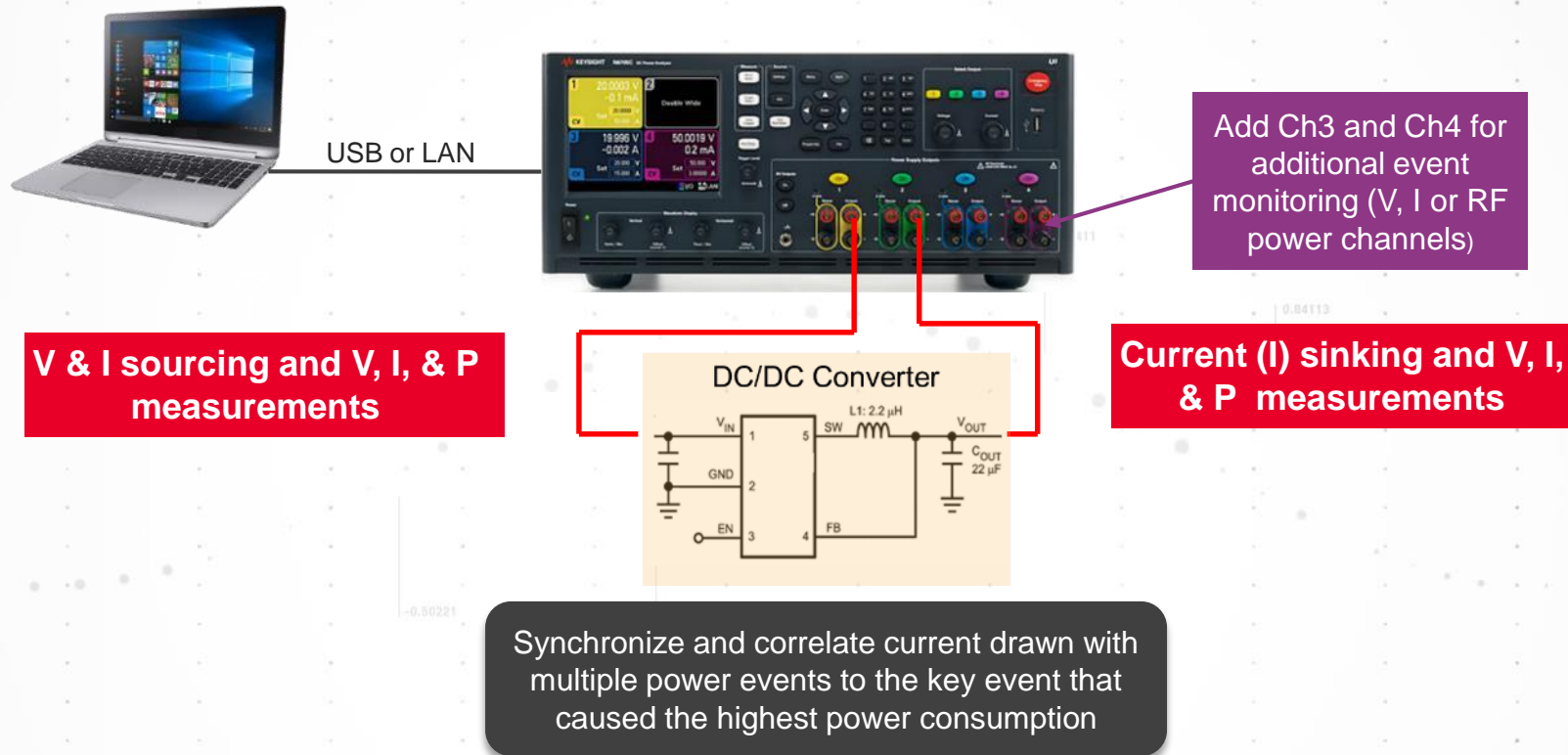


Turn-on time



V_{out} rise time

Other Application #2: DC-DC Converters Measurements



- X8712A's (N6705C + 2x N6781A) compact size allows placement close to thermal chamber
- Customer making radio communication products can now perform new tests like:
 - V ramp testing
 - I load ramp testing

Other Application #3: Wireless Charging and Efficiency



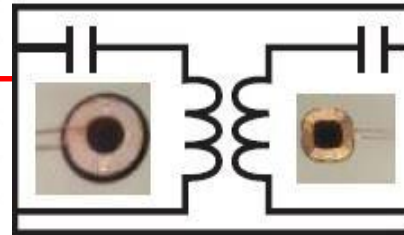
- Simulates charger V & I sourcing
- Measures V, I, & P



USB or LAN



- Simulates battery V & I
- Measures V, I, & P (mAh)



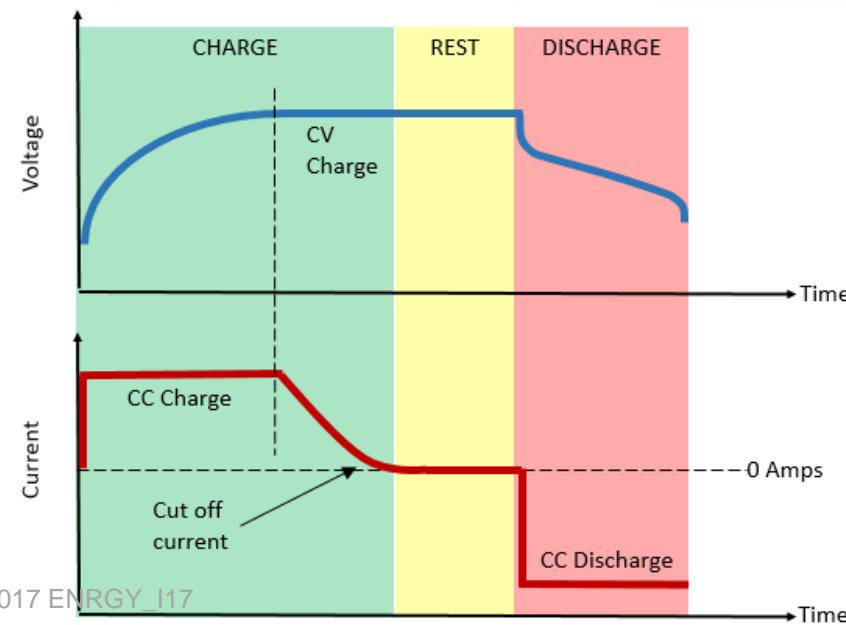
Dual-channel power system for wireless charging efficiency test:

- Channel-1 simulate 5V charger
- Channel-2 simulates the battery and calculates charge efficiency in real time

Other Application #4: What is cell characterization?

- Testing to determine:
 - Cell capacity (Ah), internal resistance
 - How capacity varies with age, discharge rate, cell temp
 - Cell voltage vs. SoC (family of curves for different discharge rates, temps)
- Done by one or more charge and discharge cycles.
- Fundamental measurements are current, time, voltage, temperature.
- Classic test done for many years. Many vendors at various performance levels.

- Also known as cell or battery “cycling” or “cyclers”
 - Classic method is CC-CV Charge – Rest – CC Discharge.
 - *What if this pattern doesn't match the actual application?*



Other Application #4: Cell and Battery Characterization Platform

Charge-Discharge-Measurement

- High-accuracy measurement of
 - Cell capacity (Ah) and energy (Wh)
 - Internal resistance
 - Current, voltage, temperature, power
- User-controlled dynamic charge-discharge algorithms
- Individual channelized charge/discharge instrumentation allows for different tests to run on each channel, and easy scaling of number of channels.



MPS

- For low power cells & batteries
- Up to 20V, up to +/- 8A



APS

- For high power cells and batteries
- Up to 160V, up to +/-200A
- Can parallel for higher power



34972A

- Cell temperature



Other Power Consumption Test Solutions



CX3300 device current
waveform analyzer



X8711A

一種全新的 IoT 終端功能測試方案



為什麼是OTA Signaling信令測試?

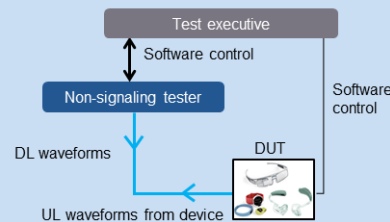
SIGNALING VS NON-SIGNALING TEST

- 特別小的產品, 沒有測試接口
- 不需要特定的晶片控制或驅動
- 適用於最終的產品應用軟件測試



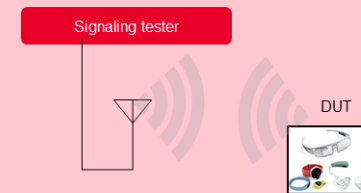
非信令测试

Non-signaling test, or test mode, is carried out by putting the device-under-test (DUT) into a known state, allowing test equipment to measure predefined transmission patterns.













信令测试

Signaling test is conducted with test equipment emulating a base station that sends a signal, and the device-under-test (DUT) that will respond to the signal.



Characteristics

	Requires wired connection		Conducts testing over-the-air (OTA)
	Uses test firmware to test in predefined test mode		Uses commercial firmware to test in the DUT's operating mode
	Requires chipset control		Do not require DUT control.
	Covers a comprehensive list of test parameters		Performs only basic TX/RX tests during final verification tests
	Often used in high volume chipsets or modules manufacturing		Often used as end-of-line (EOL) manufacturing test of end devices or pre-test for complex system

X8711A IoT Device Functional Test Solution

DESIGN VALIDATION AND MANUFACTURING TEST OF IOT DEVICES

Test Challenges

- IoT devices are becoming smaller and integrated, and no longer has I/O footprint for DUT control.
- Conventional non-signaling test via DUT control using physical I/O is time consuming. The set up process is complicated and requires access to chipset for controlling the DUT.



Keysight Solution

- IoT Device Functional Test solution provides Over-the-Air BLE and WiFi tests.
- The solution is complete with shield-box and TAP based software applications.



Customer Benefits

- Test IoT devices in actual operation mode and in its final form
- Assure the devices meet quality levels and that there is less risk of manufacturing defects or field failures
- Maximize throughput on the manufacturing line and accelerate time to market
- Simplify test development with the TAP measurement suites

- ✓ **Up to 4X reduction in test time**
- ✓ **Faster test development – no DUT control required**
- ✓ **Simple set up**

X8711A IoT Device Functional Test Solution

KEY SPECIFICATIONS



Key Specifications:

Output Power (Rx sensitivity measurements):

BLE Output: -40 to -90 dBm, 0.5dB step; accuracy ± 2 dB

WiFi Output: -33 to -73 dBm, 0.5dB step; accuracy ± 2 dB

RF Power measurement (Tx power measurements) :

Range: 0 to -30 dBm at RFIO port

Accuracy: ± 2 dB

Test Parameters	RF Module (BLE/WLAN)	Power Supply (optional)
DC Test <ul style="list-style-type: none"> Power On/Off DC Power measurement 		<ul style="list-style-type: none"> ✓ ✓
RF/Radio Test		
<ul style="list-style-type: none"> Radio Format 	BLE 4.2, WLAN 802.11b/g/n (BT5.0 & Zigbee upgrade option)	
<ul style="list-style-type: none"> Tx RF Power 	✓	
<ul style="list-style-type: none"> Rx PER Test 	✓	
<ul style="list-style-type: none"> Rx Sensitivity Test 	✓	

BLE 4.2 System Software

SAMPLE SCREENSHOT

Initial configurations

Device discovery & connection

Active Scan PER test

Connect Request PER test

TX power measurement

Data logging

Setting configurations

Test results

Test log

Step Name	Verdict	Message	Result	Duration	Step Type
Configure 34999A Instrument				0.00 s	IoT Device Tests \ Configure 34999A Instrume
Configure Simple CSV Listener				0.00 s	IoT Device Tests \ Configure Simple CSV Liste
0. Set System Offsets				0.00 s	IoT Device Tests \ BLE \ Set System Offsets
1. BLE Device Discovery	Pass	24:71:89:CC:19:82 Active Scan Connect Request		14.03 s	IoT Device Tests \ BLE \ BLE Device Discovery
2. BLE Device Selected	Pass			4.94 s	Flow Control \ If Verdict
2.1 For Active Scan or Connect Request Device	Pass			4.94 s	Flow Control \ If Verdict
2.1.1 Measure Advertising Interval					IoT Device Tests \ BLE \ Measure Advertising
2.1.2 Set BLE DL Power				1.16 s	IoT Device Tests \ BLE \ Set BLE DL Power
2.1.3a For Active Scan Device	Pass			3.78 s	Flow Control \ If Verdict
2.1.3a.1 Measure Scan Response Time		Max: 199 ms, Min: 40 ms, Average: 78 ms			IoT Device Tests \ BLE \ Measure Scan Respo
2.1.3a.2 Active Scan Signaling PER test	Pass	Iteration 3 of 3 0.00 %, 0.00 %, 0.00 %		3.78 s	IoT Device Tests \ BLE \ Signaling PER \ Acti
2.1.3b For Connect Request Device					Flow Control \ If Verdict
2.1.3b.1 Connect Request Signaling PER test					IoT Device Tests \ BLE \ Signaling PER \ Conn
3. Advertising Power Measurement	Pass			4.78 s	IoT Device Tests \ BLE \ BLE Advertising Chan
4. Turn Off BLE Radio	Pass			0.59 s	IoT Device Tests \ BLE \ Turn Off BLE Radio

Status	Channel	Frequency	Power
✓	37	2.402 GHz	-11.71 dBm
✓	38	2.426 GHz	-10.51 dBm
✓	39	2.48 GHz	-10.06 dBm

```
Log
Errors 0 Warnings 0 Information 68 Debug 29
14:25:38.608 Summary 4. Turn Off BLE Radio 594 ms Pass
14:25:38.608 Summary ----- TestPlan completed successfully in 30.31 s -----
14:25:38.615 Simple CSV TestPlanRunCompleted for Simple CSV. [6 ms]
14:25:38.615 Simple CSV Resource "Simple CSV" closed. [0 ms]
14:25:38.617 34999A Resource "34999A" closed. [2 ms]
```

Passed

X8711A Case Study

HEARING AID BLE SIGNALING TEST

Medical device company

A leading hearing aid product company who is currently making MFI hearing aids in Singapore with BLE integrated.



Current way / issues

- Existing BLE solution is too expensive for manufacturing
- Need cost-down options as production volume increases



New Way (X8711A beta)

- Cost-effective and cover all essential tests to verify product quality
- Reduces test time (a few minutes to < 35s)



Results

- Reduce test time by >50%
- Reduce manufacturing test cost by >20%
- Enable manufacturing test software standardization with Keysight TAP platform

“Amazing! This solution is going to streamline my manufacturing process significantly” VOC

[Download case study flyer in Chinese](#)

X8711A Case Study

AC CONTROLLER BLE SIGNALING TEST

Air conditioning system provider

This company is a leading air conditioning (AC) system provider. Their current products have already supported NFC. They are developing next generation AC controller with BLE to improve usability and maintenance operations.



Current way / issues

- Requires hardwire connection
- Complex and expensive

New Way (X8711A)

- No physical connection, enable OTA testing
- Cost-effective and cover all essential tests they need

Results

- Significant time saving in product design and verification tests
- Another group is evaluating the WLAN version of this solution
- Their subsidiaries in US and China are evaluating this solution

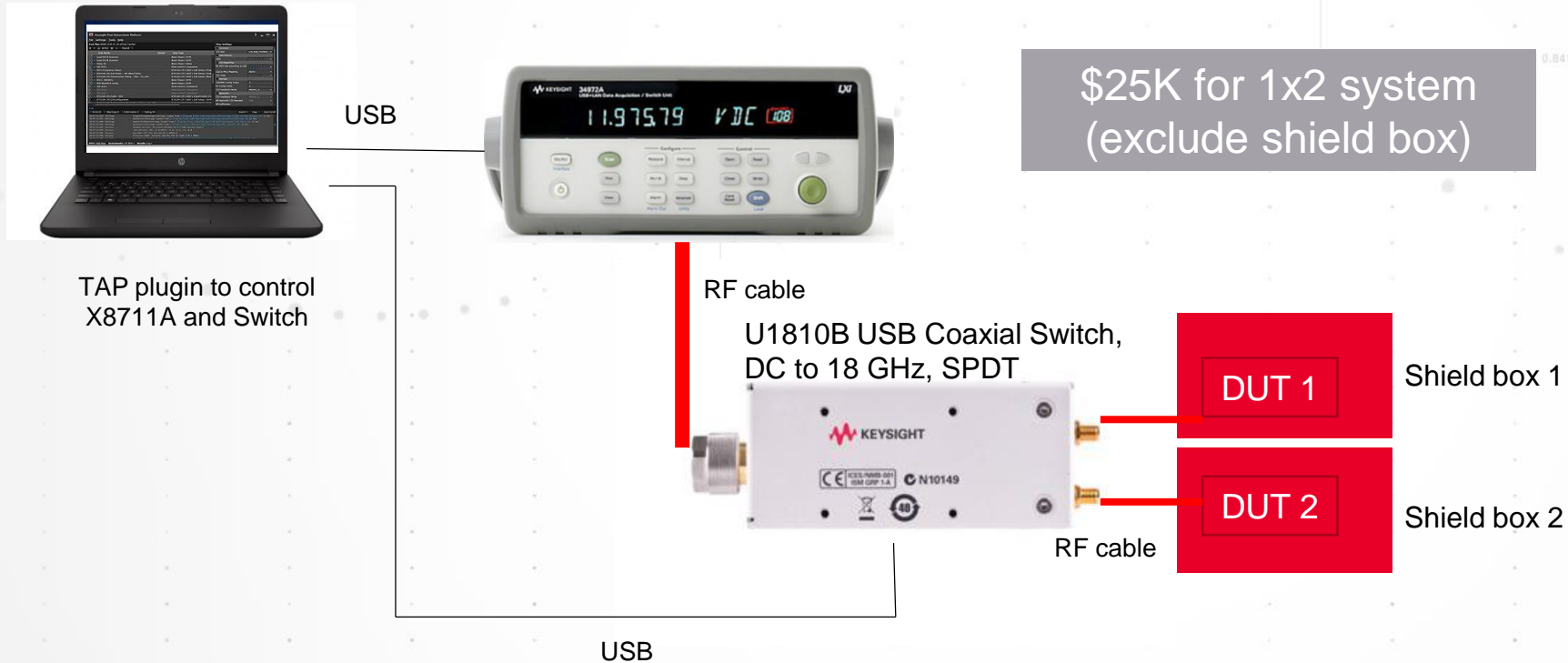
"I like the contactless test setup and the small form factor of the modular solution" - VOC

[Download case study flyer in Chinese](#)

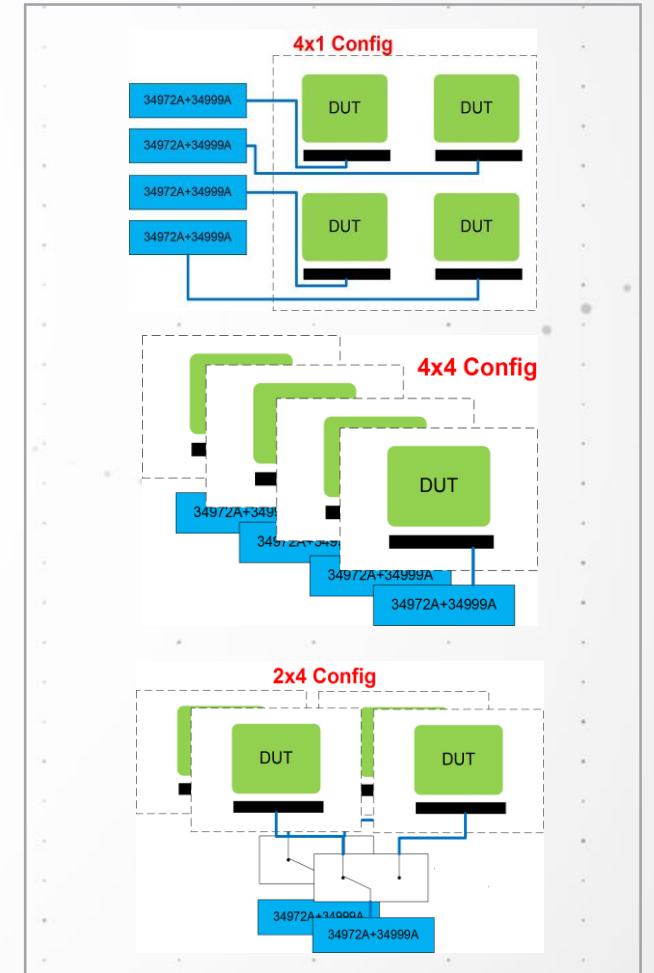
X8711A Multi-Up Configuration [Custom solution]

FOR HIGH VOLUME MANUFACTURING

Sample configuration for 1x2.



It could be any NxN configuration depending on customer's needs



X8711A new accessory – X8752A near field coupler

OTA MEASUREMENT FOR BIG APPLIANCES

Laptop / PC (Controller)



USB cable



RF cable to connect antenna coupler to the RFIO port of the X8711A



Innovative **coupling antenna design** with **great signal directivity in the front** and sufficient **shielding from the back and side** to isolate interference signals from the surrounding environment

Place near-field coupler as close as possible (< 5cm) to the wireless module of the DUT



Wireless module inside the AC (DUT)

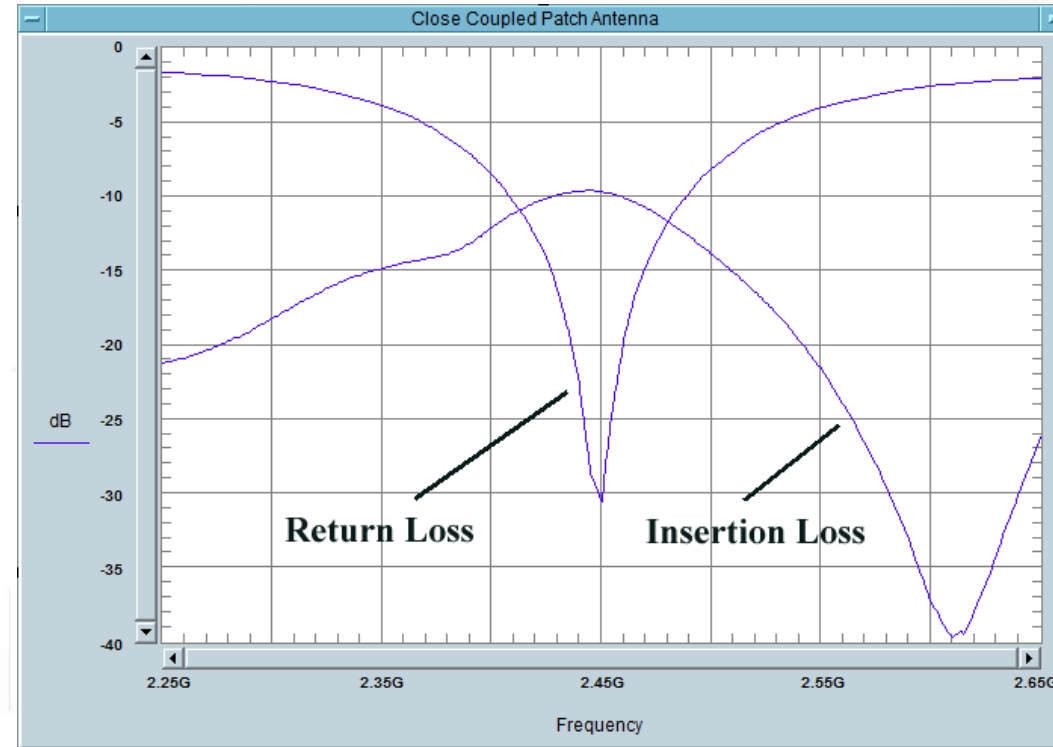
This Solution enables OTA TX/RX measurements on finished products (big appliances) in noisy environment without the need of large anechoic chamber

X8752A - Return Loss and Coupling (Insertion) Loss

- External dimensions 50mm*50mm*26mm
- Including flange 80mm*50mm*26mm



- Coupling (Insertion) loss is measured with 2 complete antennas face to face
- Equates to 2.5cm between patches



On Axis Gap	0cm	5cm	10cm	20cm	30cm
2.45GHz Loss	9dB	17dB	22dB	29dB	31dB

X8751A Shield box

As part of the X8751A RF Shield Enclosure Kit, Keysight will provide:

- One (1) Tescom TC-5910D Shield box comprised of One (1) M591012B I/O module, One (1) TC-93023B Antenna coupler, One (1) F59105A Universal grid fixture.
- One (1) RF cable.
- One (1) SMA jack to N plug adapter.
- One (1) RF terminator N 50 ohm.

Keysight will not conduct any regulatory or safety testing on the X8751A RF Shield Enclosure Kit. If this is required it will be the sole responsibility of CUSTOMERS. Customer is responsible for any additional certification testing and marking such as CE, CSA, NRTL as deemed necessary by Customer. Keysight will not evaluate EMC compliance of the system. The customer is responsible for the EMC compliance upon final system integration & configuration completed at customer assembly site.

Estimated delivery time: 7 weeks

Price: \$6,000

Note that this shield box is not available for sale in Europe due to non-RoHS compliant.



Keysight New IoT Test Solutions

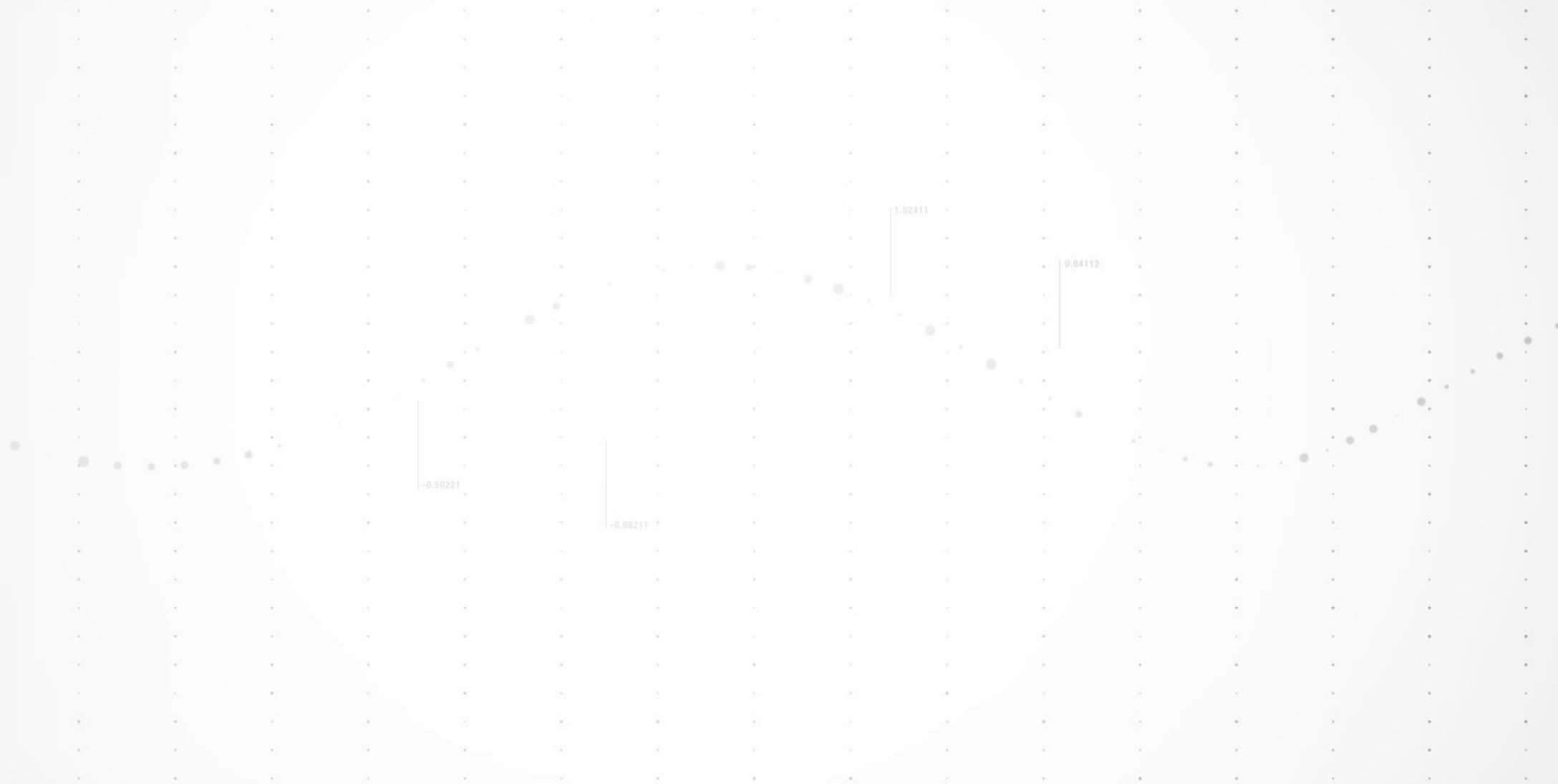


X8711A BLE/WLAN Device
Functional Test Solution



X8712A Event Based Power Analysis Solution

Back Up



Maximum N6781A Digitizing Rate Performance Summary

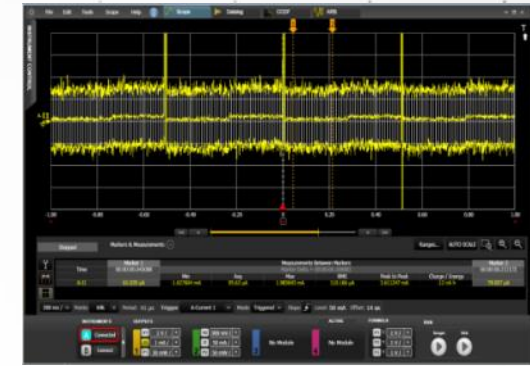
	14565 with 66319/21	N6705C with N6781A	14585A with N6705C & N6781A
Scope Capture	<ul style="list-style-type: none"> 4 kSamples 15.6 μs sample interval Can capture 64 msec @ max rate 	<ul style="list-style-type: none"> 512 kSamples (5.12 μs * # of traces) sample interval¹ Can capture 2.62 sec @ max rate 	<ul style="list-style-type: none"> 1.024 Msamples (5.12μs * # of traces) sample interval¹ Can capture 5.24 sec @ max rate
Data Logging	5 msec integration period (200 points/sec) 15.6 μ s sample interval Can capture 5 hours @ max rate	(20.48 μ s * # of traces) integration period ² (50k / # of traces) points/sec 5.12 μ s sample interval Can capture ~45 min @ max rate w/ 512 int. RAM Can capture ~6 hours @ max rate w/ 4G USB RAM	(102.4 μ s * # of traces) integration period ² (10k / # of traces) points/sec 5.12 μ s sample interval Writes to PC hard drive. Capture time limited only by available space
CCDF/Histogram Logging	15.6 μ s sample interval Up to 1K hrs @ any rate	Not Available	20.48 μ s sample interval Up to 1K hrs @ any rate

Notes:

1. The sample interval time is proportional to number of measurement traces selected. Power traces are calculated so they do not increase sample interval time.
2. The integration period is effectively the sample interval for data logging, with the 5.12 μ s the underlying rate of sampling that gets averaged into the integration period. Likewise, the integration period is proportional to the number of measurement traces selected excluding power traces which are calculated.

14585A Control and Analysis Software

- Compliments N6705C by enhancing & adding capabilities through a PC graphical user interface:
 - Simultaneously control & display up to 4 N6705Bs / 16 outputs
 - Large PC monitor greatly enhances viewing details
 - Data log direct to PC hard drive, limited only by available space
 - Doubles scope mode memory space (1.024 Meg vs. 512 K)
 - Enables battery drain analysis testing (battery run-down, statistics)
 - Adds statistics capabilities (histogram & CCDF) with direct logging for N6781A BDA SMU module only and data logging conversion for others
 - Adds more ARB waveform generation capabilities; new pre-configured waveforms, formula-based generation, record and playback
 - Formula-based traces available enable re-scaling and unit conversion
 - Works with new and existing 22 modules; useful for a lot more than just Battery Drain Analysis
- Some limiting considerations
 - External app; limits data-logging maximum speed (10 Ksps vs. 50 Ksps for the N6705C mainframe directly)



Scope Mode



Data Log Mode



Statistics Mode

Keysight IoT Battery Drain Test Solutions

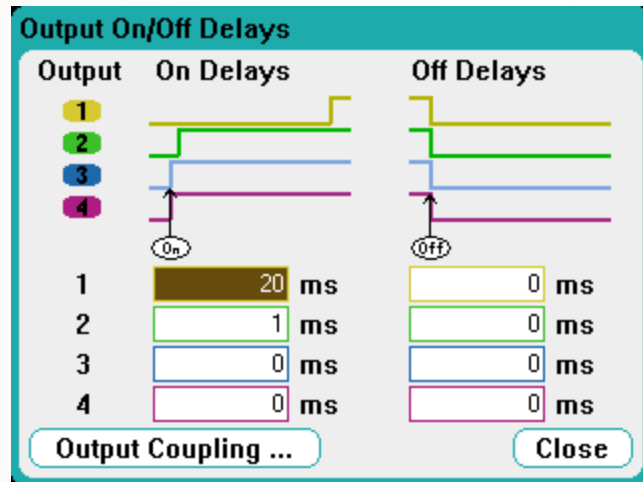
For more info, refer to AN: Battery drain analysis for low power IoT devices:

<http://literature.cdn.keysight.com/litweb/pdf/5992-1765EN.pdf>

	34470 DMM	N2820A scope probe	N6705C + N6781A	B2900 SMU	CX3300 DCWA
Display size	4.3"	Scope dependent	5.9"	4.3"	14.1"
BW, sample rate	17 kHz, 50 kSA/s	500 kHz, 5 Gsa/s	29 kHz, 200 kSa/s	10 kHz, 100 kSa/s	140 MHz, 1 GSa/s
Meas. Res	14 bits	14 bits	18/ 28 bits	20 bits	14 bits
Min measurable static current	10 pA	500 nA	800 nA	1 pA	150 pA
Min measurable dynamic current	10 nA	500 nA	1.4 uA	10 fA	150 pA
Max meas current	10 A	5 A	3 A	3 A	10 A
Min/Max source current	None	None	3 A	3 A	None
Burden voltage	27 mV	1 mV	0 mV	0 mV	4 mV
Price	+	++	++	++	++++
Typical use	R&D / Mfg	R&D	R&D / Mfg	R&D	R&D

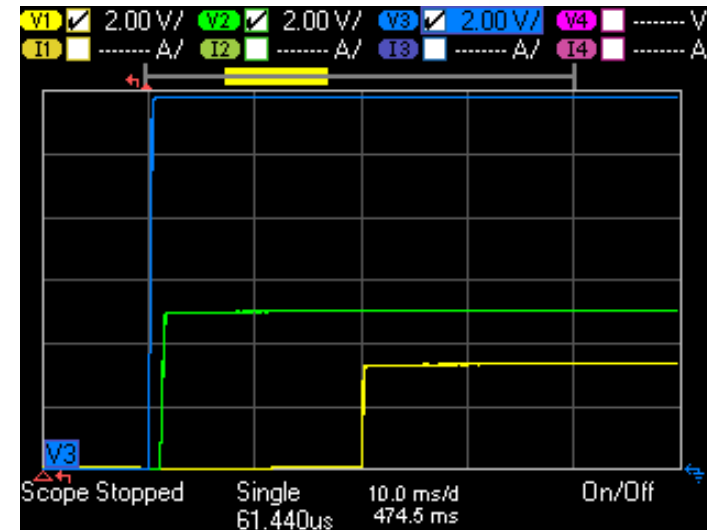
Example Application: Design Validation of PC Motherboard (continued)

- **Solution:** N6705A output sequencing was used to precisely time the individual power inputs to the board isolating the problem and helping to define the PC power supply turn-on sequence requirements



Output sequencing setup

- Output 3: 12V comes on first (0ms delay)
- Output 2: 5V follows 1ms later
- Output 1: 3.3V turns on 19ms later at 20ms
- Experiment with settings to isolate problem



Scope view

- Shows turn-on sequence
- 12V & 5V must always be > 3.3V

Capacity vs. Discharge Rate Characteristics

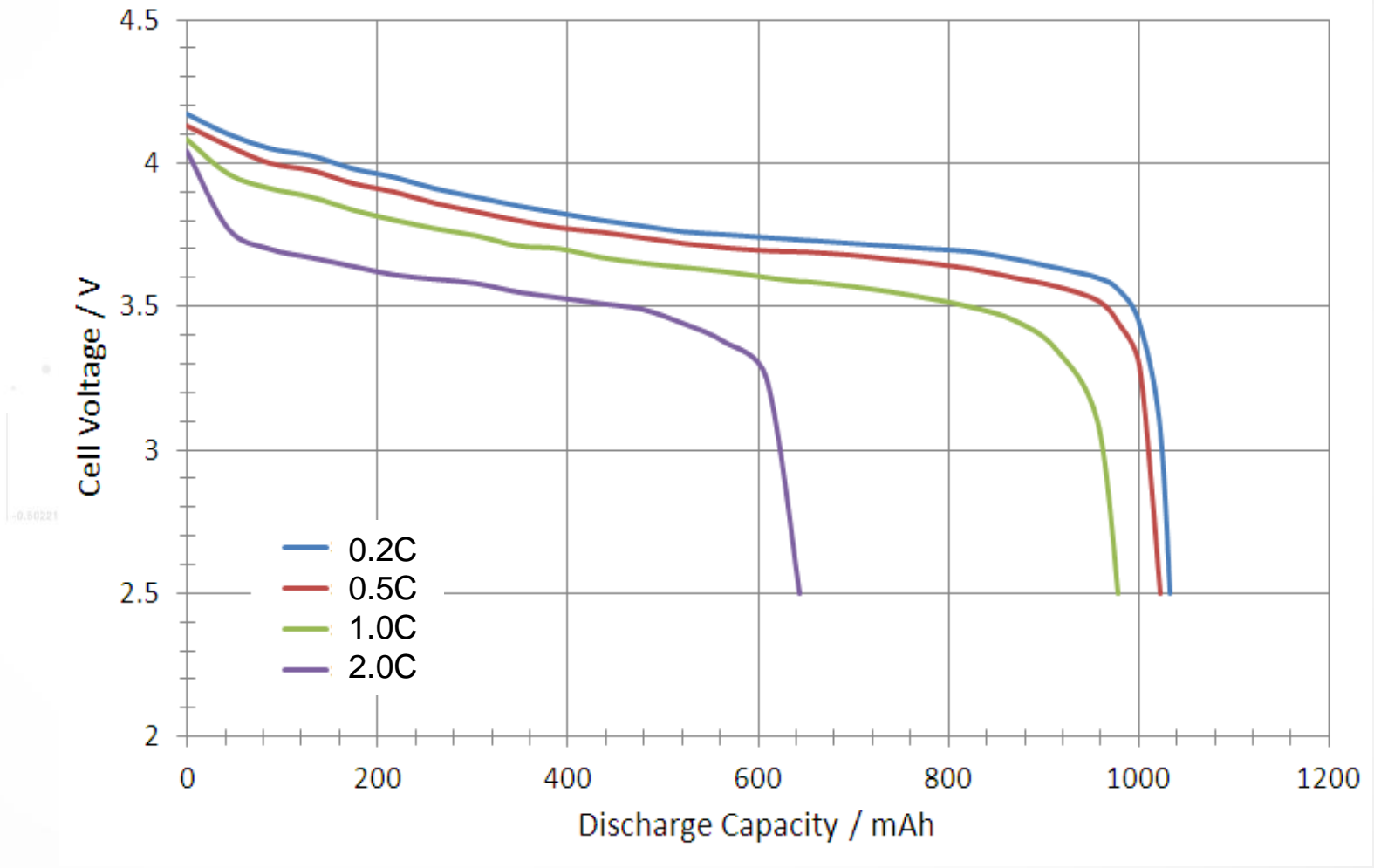
Prismatic Lithium Ion Cell Example

Cell Parameters:

- Capacity rating: 1,000 mAh
 - 0.2C (200mA), 4.2V float to 0.02C (2%) CCCV charge
 - 0.2C (200 mA) discharge
 - 3V cutoff voltage (2.75V also often specified)
 - 20 °C ambient

- ~99% of capacity for 0.5C
- ~95% of capacity for 1C
- ~62% of capacity for 2C

- Energy rating: 3.7 Wh:
 - 3.7 V rating for 0.2C discharge



1,000 mAh Lilon cell capacity vs. C rate loading